

Application/Control No.	Applicant(s)/Patent under Reexamination LEE ET AL.	
10/643,052		
Examiner	Art Unit	
Drew E. Becker	1794	

	SEARCHED				
Class	Subclass	Date	Examiner		
Sard	yrdetel	11/26/57) = 17		
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	